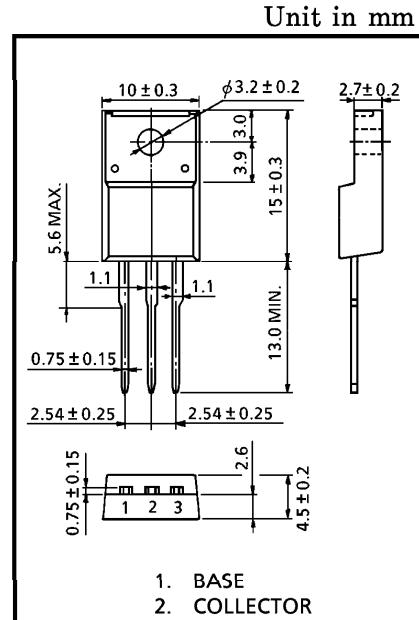


TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL TYPE

## 2SD2241

## SWITCHING APPLICATIONS

- High DC Current Gain :  $h_{FE} = 2000$  (Min.)
- Low Saturation Voltage :  $V_{CE}(\text{sat}) = 1.5V$  (Max.)
- Complementary to 2SB1481

MAXIMUM RATINGS ( $T_a = 25^\circ\text{C}$ )

CHARACTERISTIC		SYMBOL	RATING	UNIT
Collector-Base Voltage		$V_{CBO}$	100	V
Collector-Emitter Voltage		$V_{CEO}$	100	V
Emitter-Base Voltage		$V_{EBO}$	5	V
Collector Current	DC	$I_C$	$\pm 4$	A
	Pulse	$I_{CP}$	$\pm 6$	
Base Current		$I_B$	0.3	A
Collector Power Dissipation	$T_a = 25^\circ\text{C}$	$P_C$	2.0	W
	$T_c = 25^\circ\text{C}$		25	
Junction Temperature		$T_j$	150	$^\circ\text{C}$
Storage Temperature Range		$T_{stg}$	$-55 \sim 150$	$^\circ\text{C}$

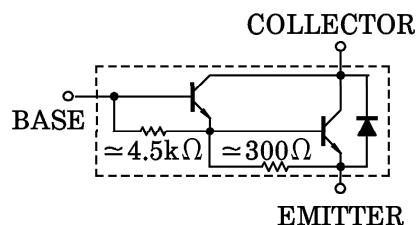
JEDEC —

EIAJ SC-67

TOSHIBA 2-10R1A

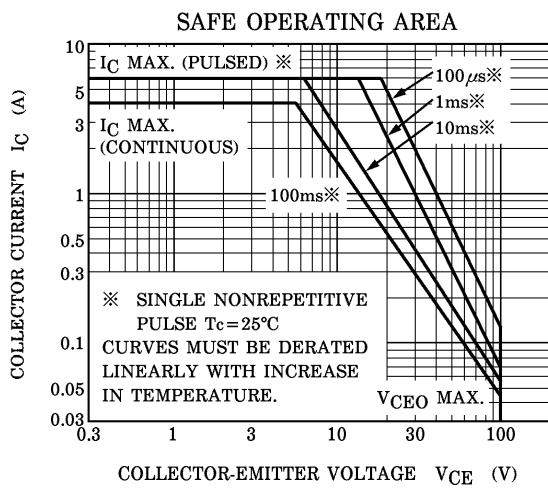
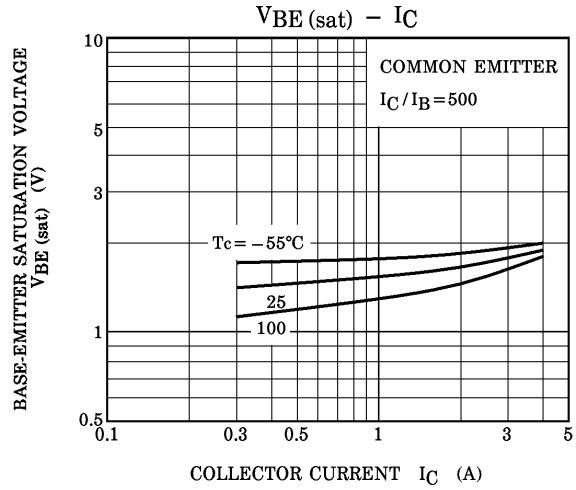
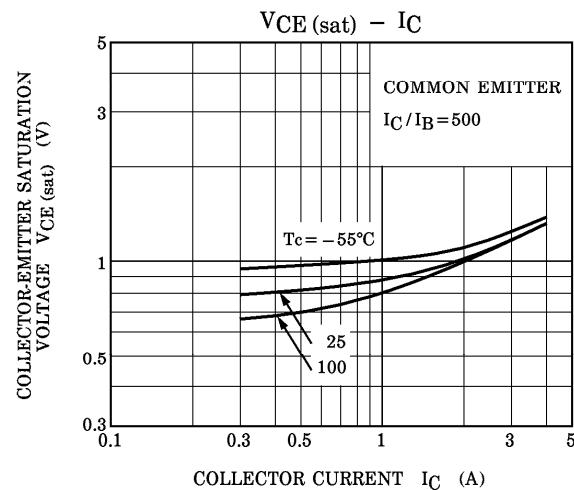
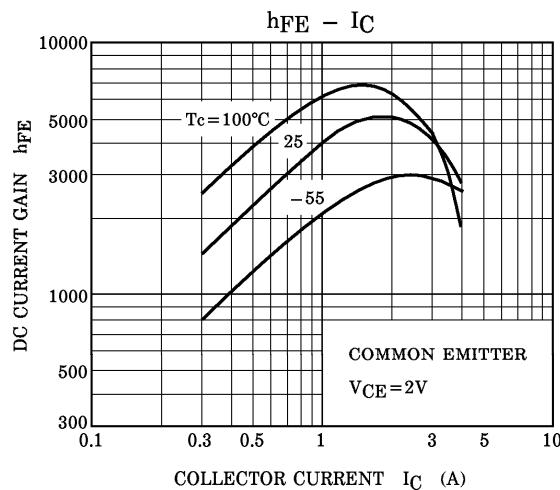
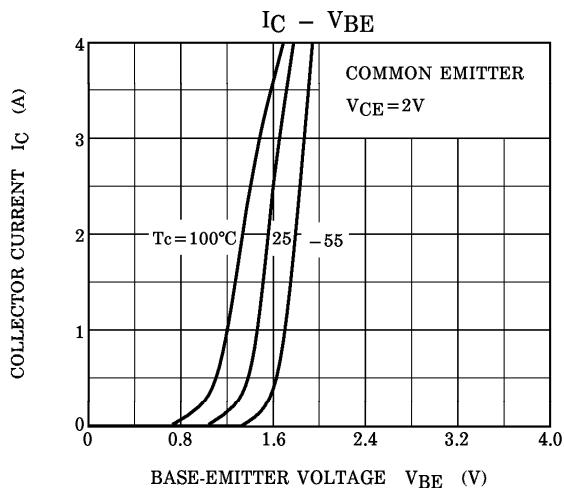
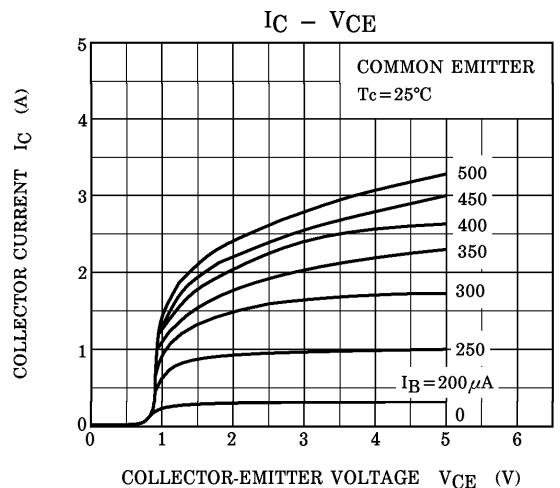
Weight : 1.7g (Typ.)

## EQUIVALENT CIRCUIT



ELECTRICAL CHARACTERISTICS ( $T_a = 25^\circ\text{C}$ )

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	$I_{CBO}$	$V_{CB} = 100\text{V}, I_E = 0$	—	—	20	$\mu\text{A}$
Emitter Cut-off Current	$I_{EBO}$	$V_{EB} = 5\text{V}, I_C = 0$	—	—	2.5	$\text{mA}$
Collector-Emitter Breakdown Voltage	$V_{(\text{BR})\text{CEO}}$	$I_C = 10\text{mA}, I_B = 0$	100	—	—	$\text{V}$
DC Current Gain	$h_{FE}$ (1)	$V_{CE} = 2\text{V}, I_C = 1.5\text{A}$	2000	—	—	$\text{V}$
	$h_{FE}$ (2)	$V_{CE} = 2\text{V}, I_C = 3\text{A}$	1000	—	—	
Collector-Emitter Saturation Voltage	$V_{CE(\text{sat})}$	$I_C = 3\text{A}, I_B = 6\text{mA}$	—	—	1.5	$\text{V}$
Base-Emitter Saturation Voltage	$V_{BE(\text{sat})}$	$I_C = 3\text{A}, I_B = 6\text{mA}$	—	—	2.0	$\text{V}$
Emitter-Collector Forward Voltage	$V_{ECF}$	$I_E = 1\text{A}, I_B = 0$	—	—	2.0	$\text{V}$
Switching Time	Turn-on Time	$t_{on}$		—	0.2	—
	Storage Time	$t_{stg}$		—	1.5	—
	Fall Time	$t_f$		—	0.6	—



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